


Search Notes 	Application/Control No. 10666319	Applicant(s)/Patent Under Reexamination WILSON ET AL.
	Examiner ERIN D CHIEM	Art Unit 2883

SEARCHED			
Class	Subclass	Date	Examiner
385	70-72, 89-94	5/21/08	edc

SEARCH NOTES		
Search Notes	Date	Examiner
wafer same (micro adj lens microlens) and (microlens micro adj lens) same align\$4	12/5/08	edc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--